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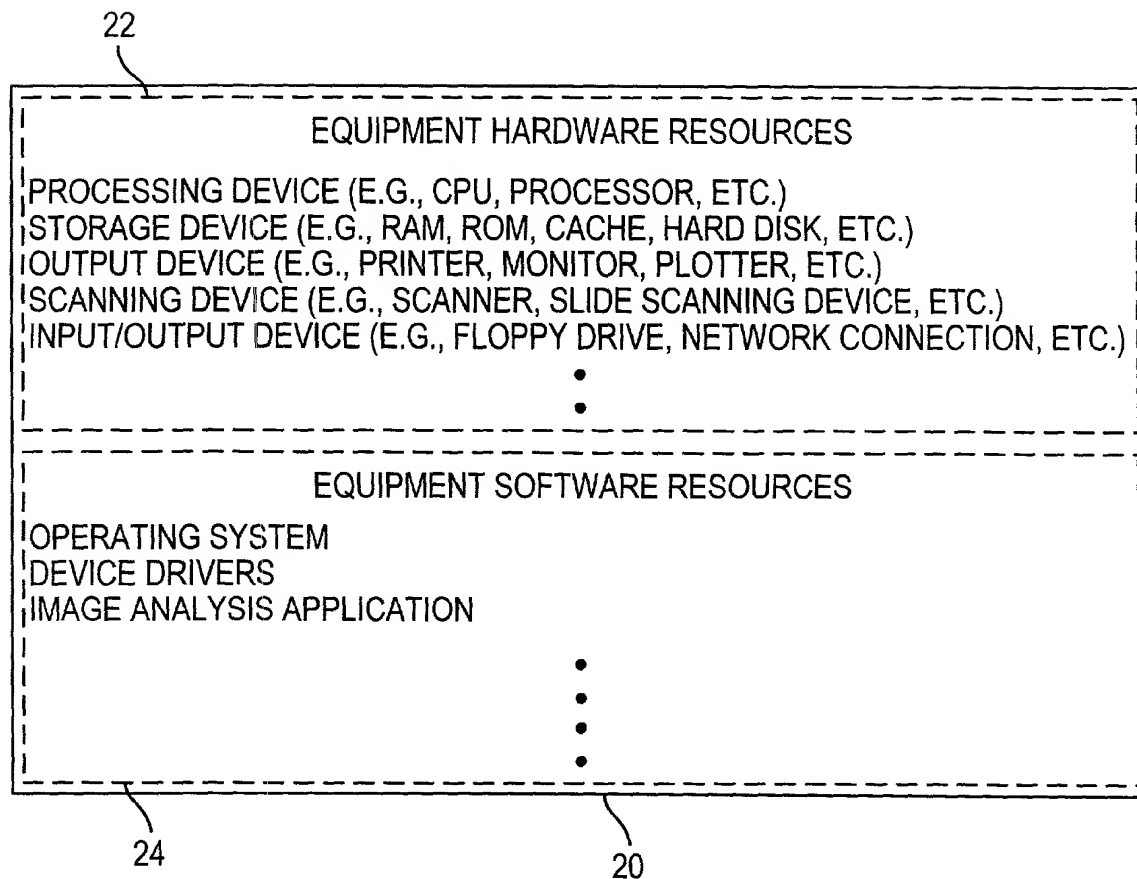


FIG. 1

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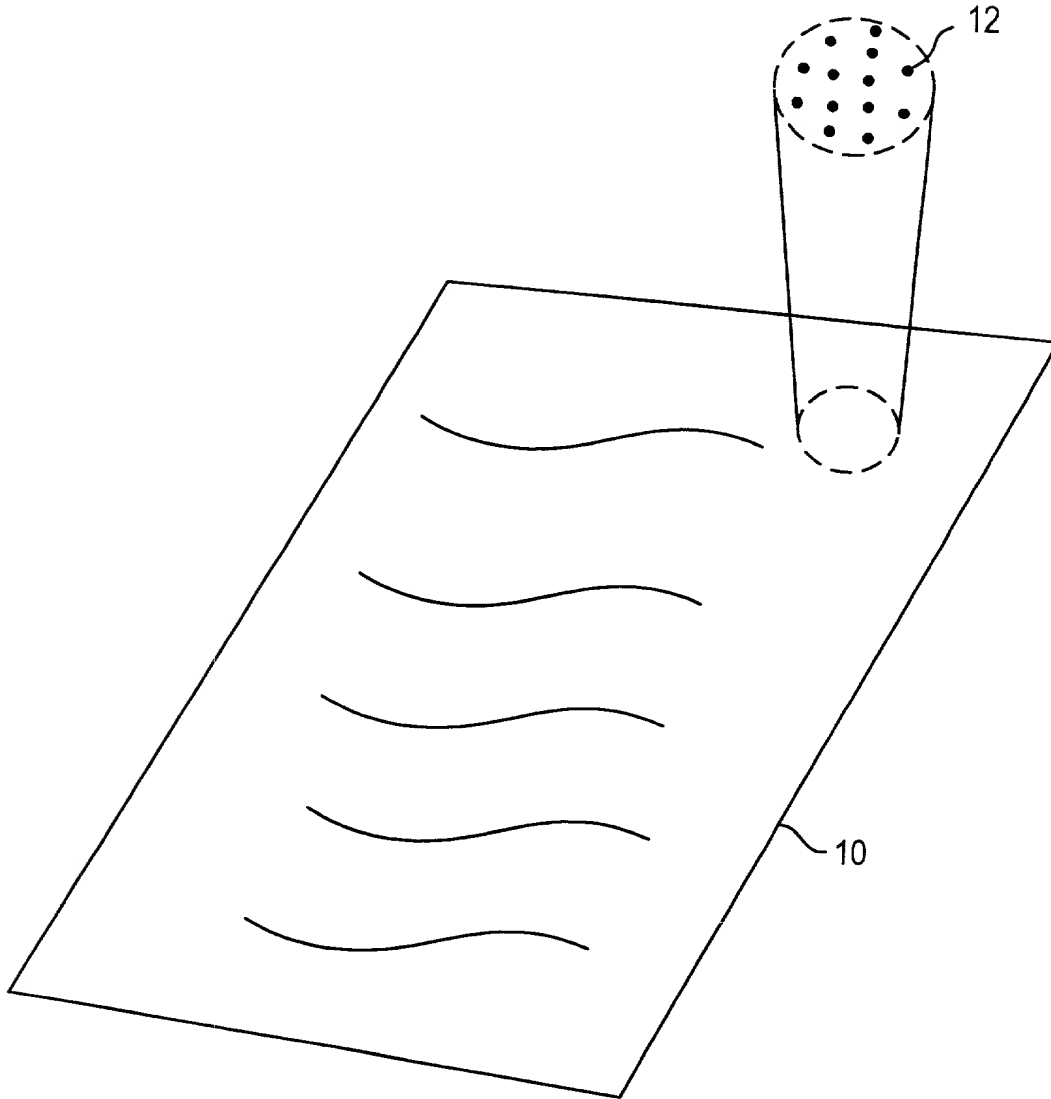
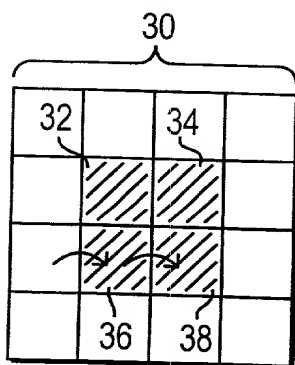
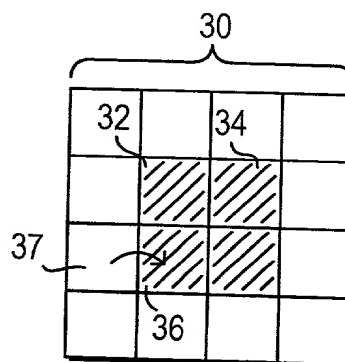
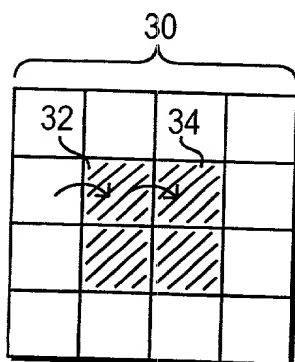
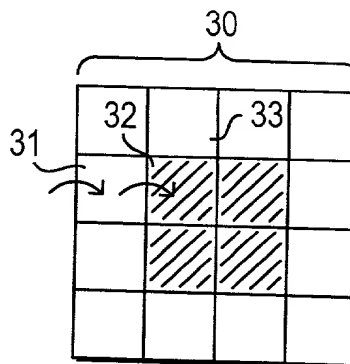
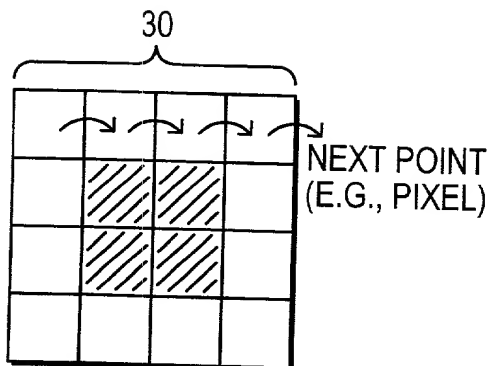


FIG. 2

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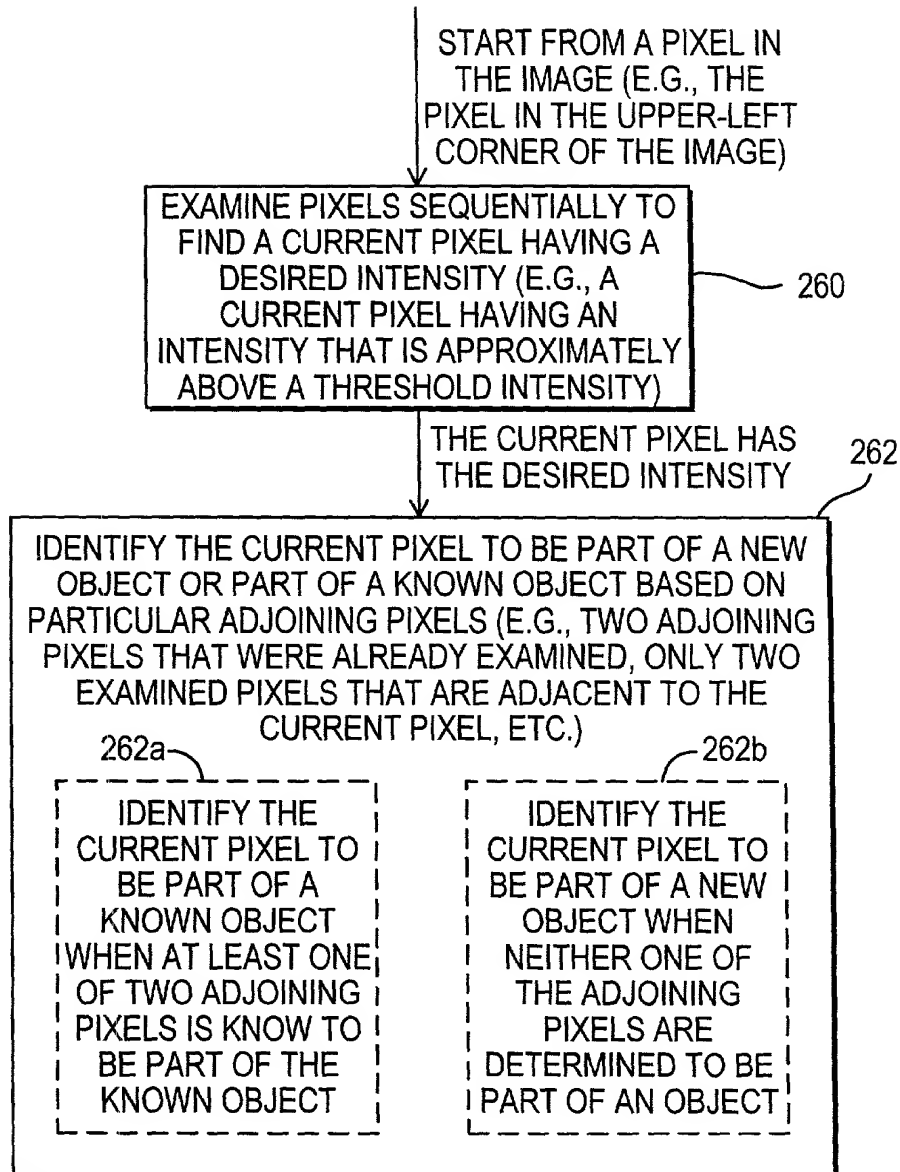
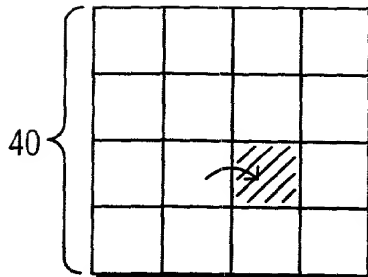


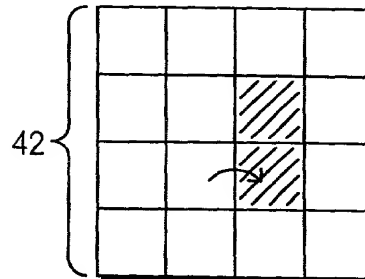
FIG. 3f

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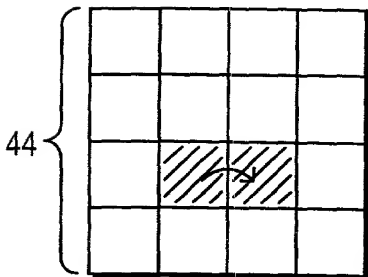
NEW SPOT

FIG. 4a



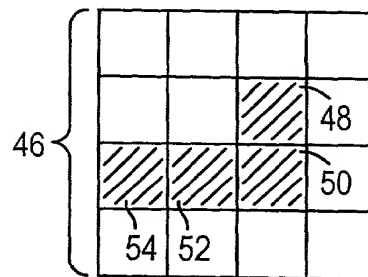
KNOWN SPOT

FIG. 4b



KNOWN SPOT

FIG. 4c



TWO KNOWN SPOTS

FIG. 4d

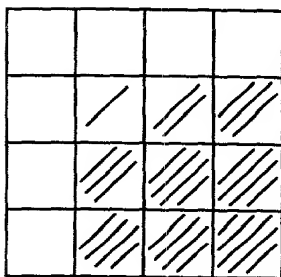


FIG. 4e

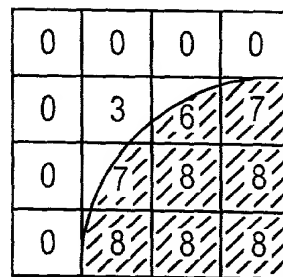


FIG. 4f

LIGHT INTENSITY RANGE

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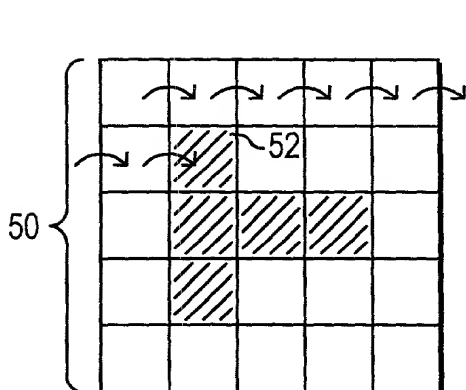


FIG. 5a

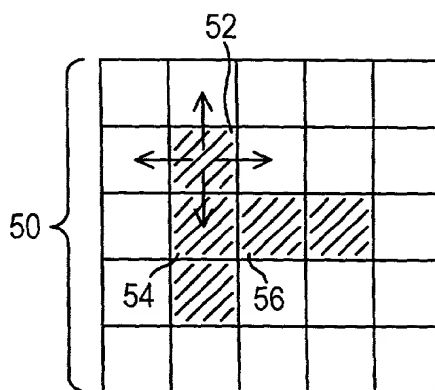


FIG. 5b

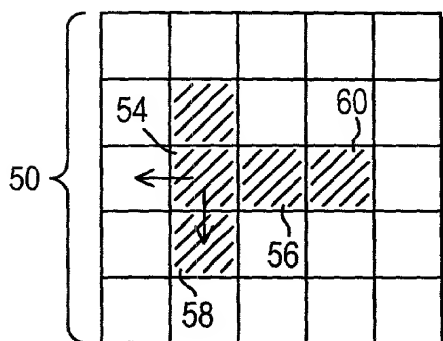


FIG. 5c

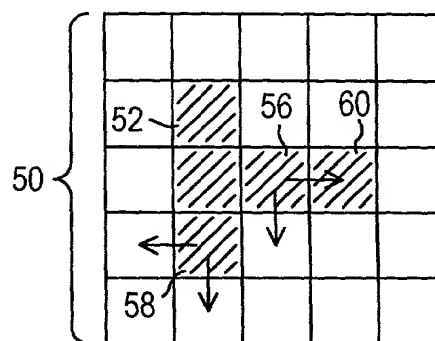


FIG. 5d

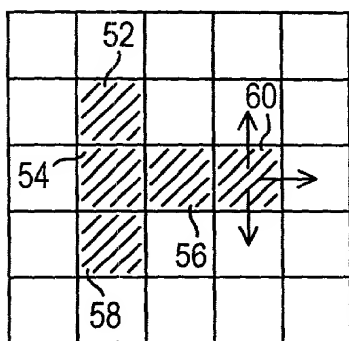


FIG. 5e

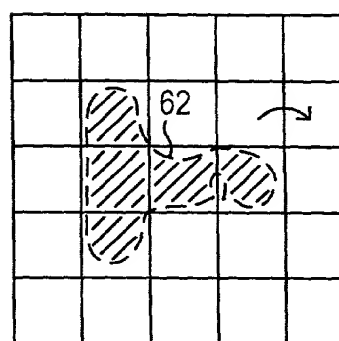


FIG. 5f

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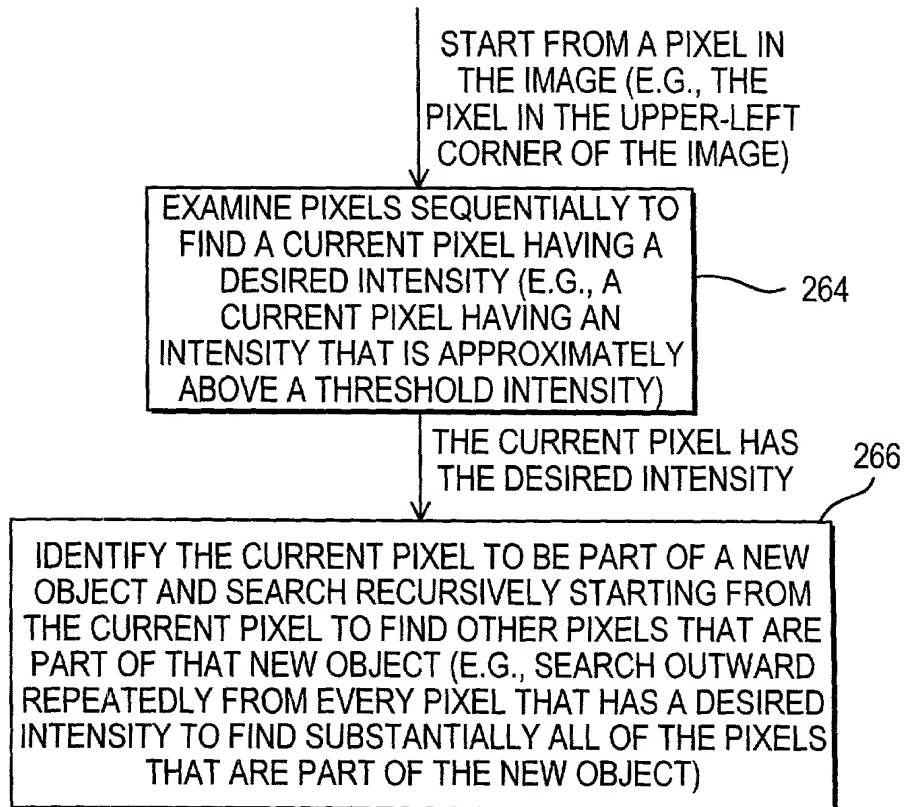
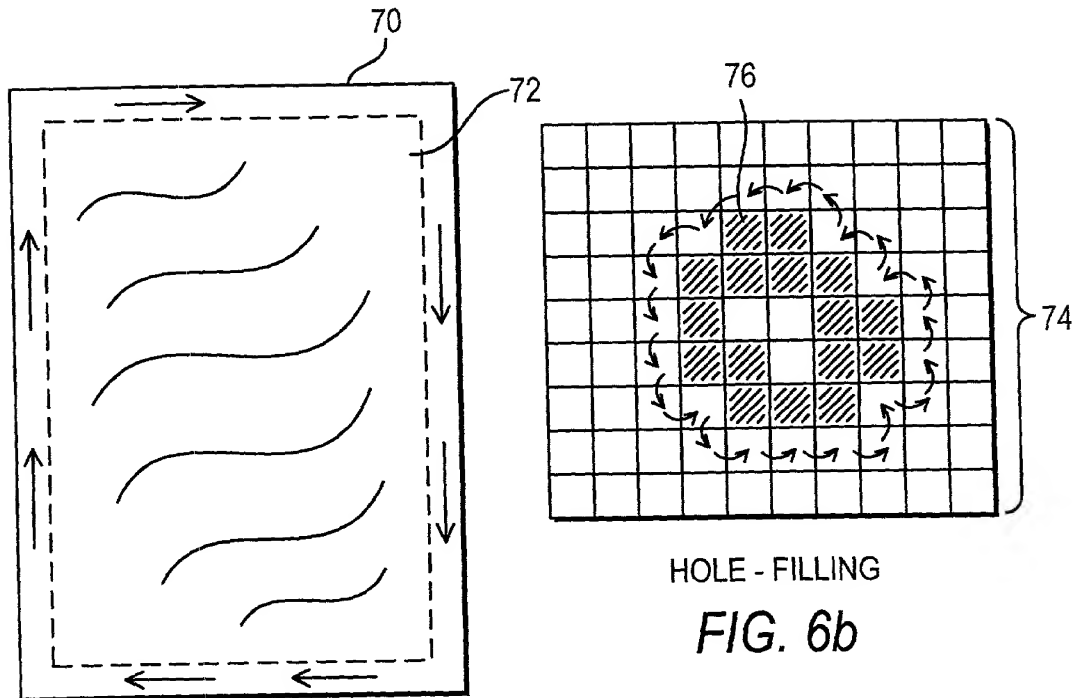


FIG. 5g

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EDGE REJECTION

FIG. 6a

HOLE - FILLING

FIG. 6b

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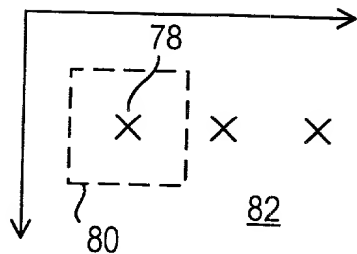


FIG. 7a

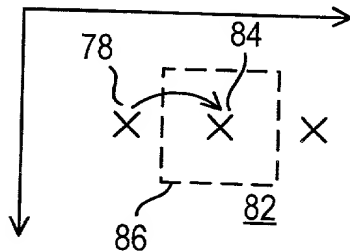


FIG. 7b

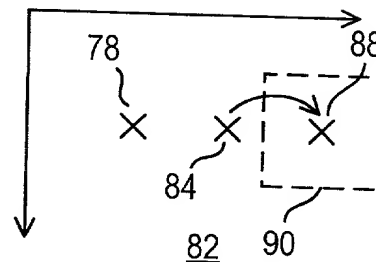


FIG. 7c

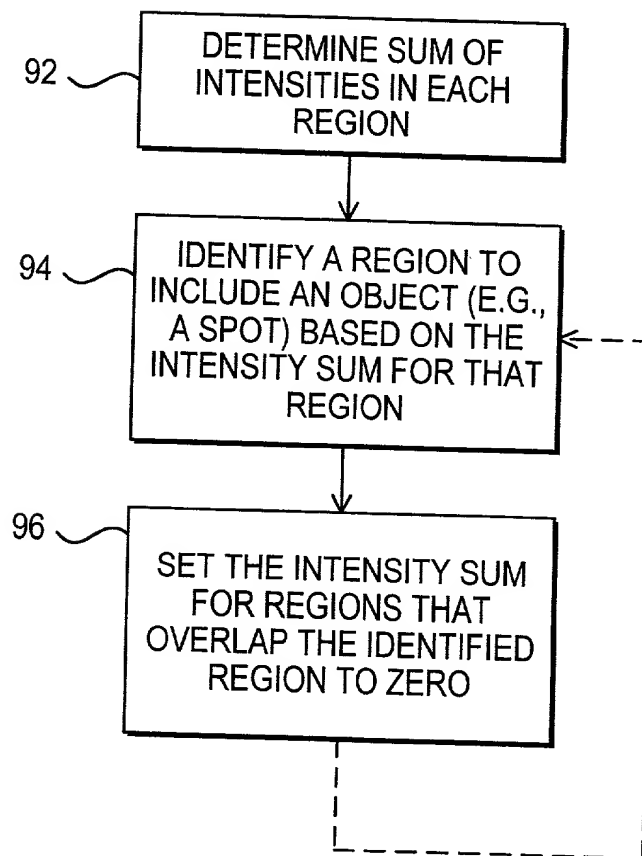


FIG. 8a

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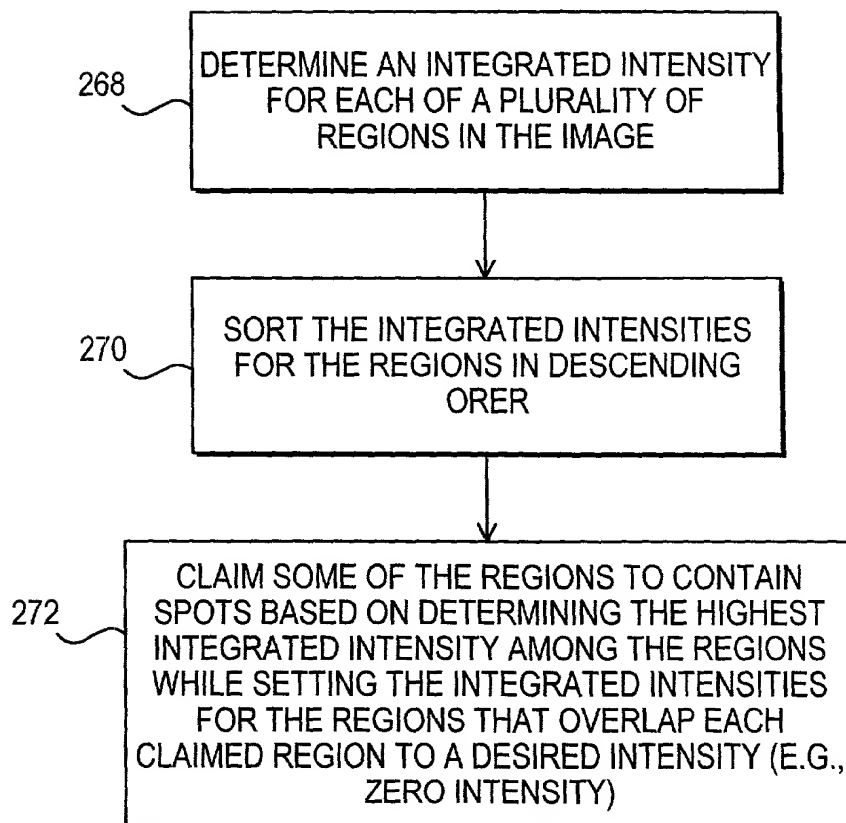


FIG. 8b

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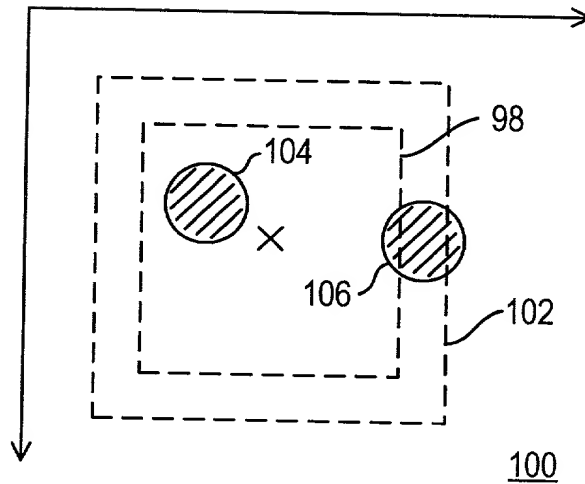


FIG. 9

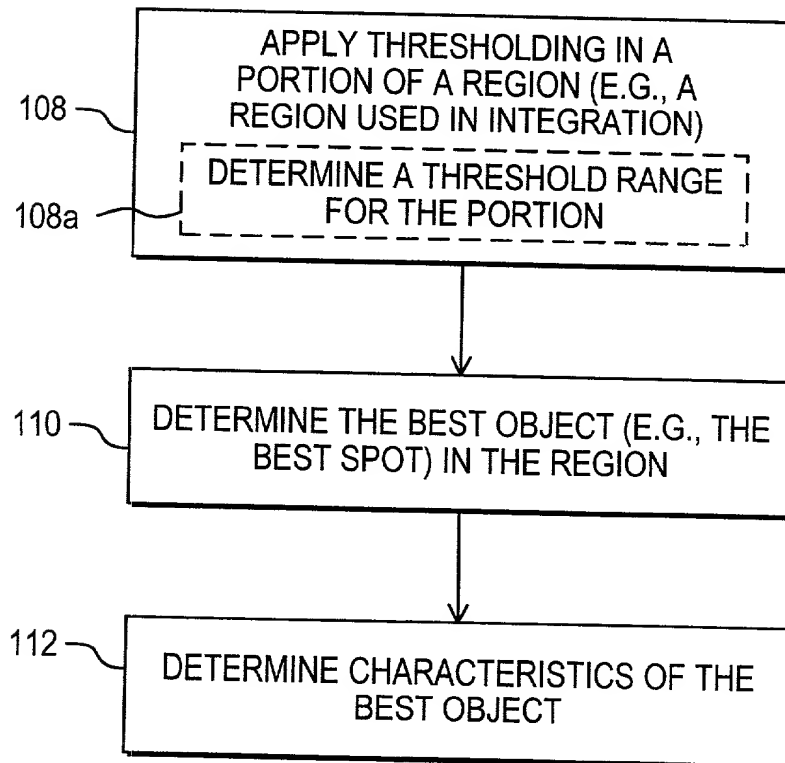


FIG. 10

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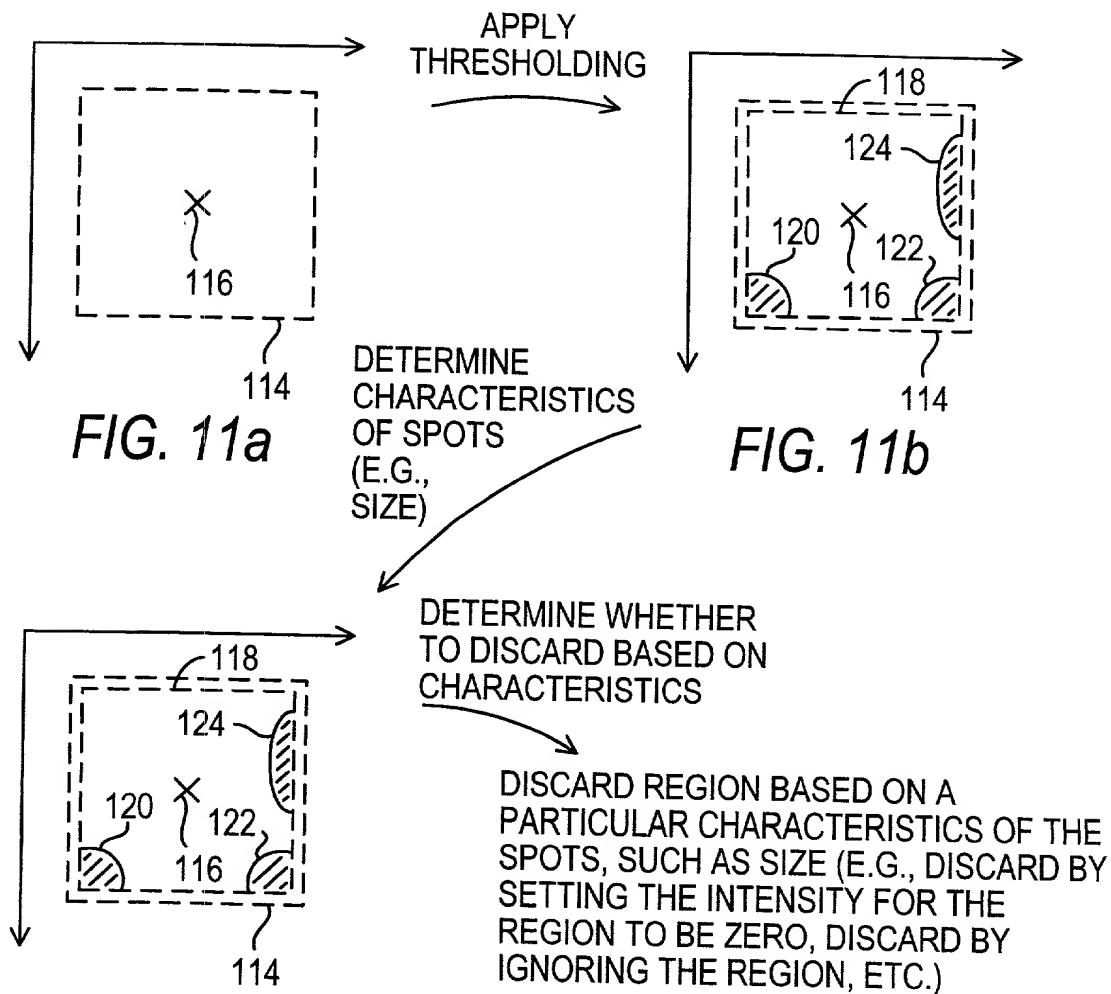


FIG. 11c

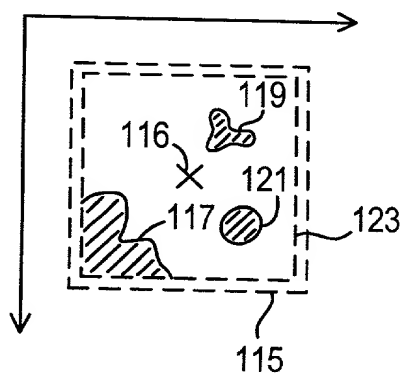
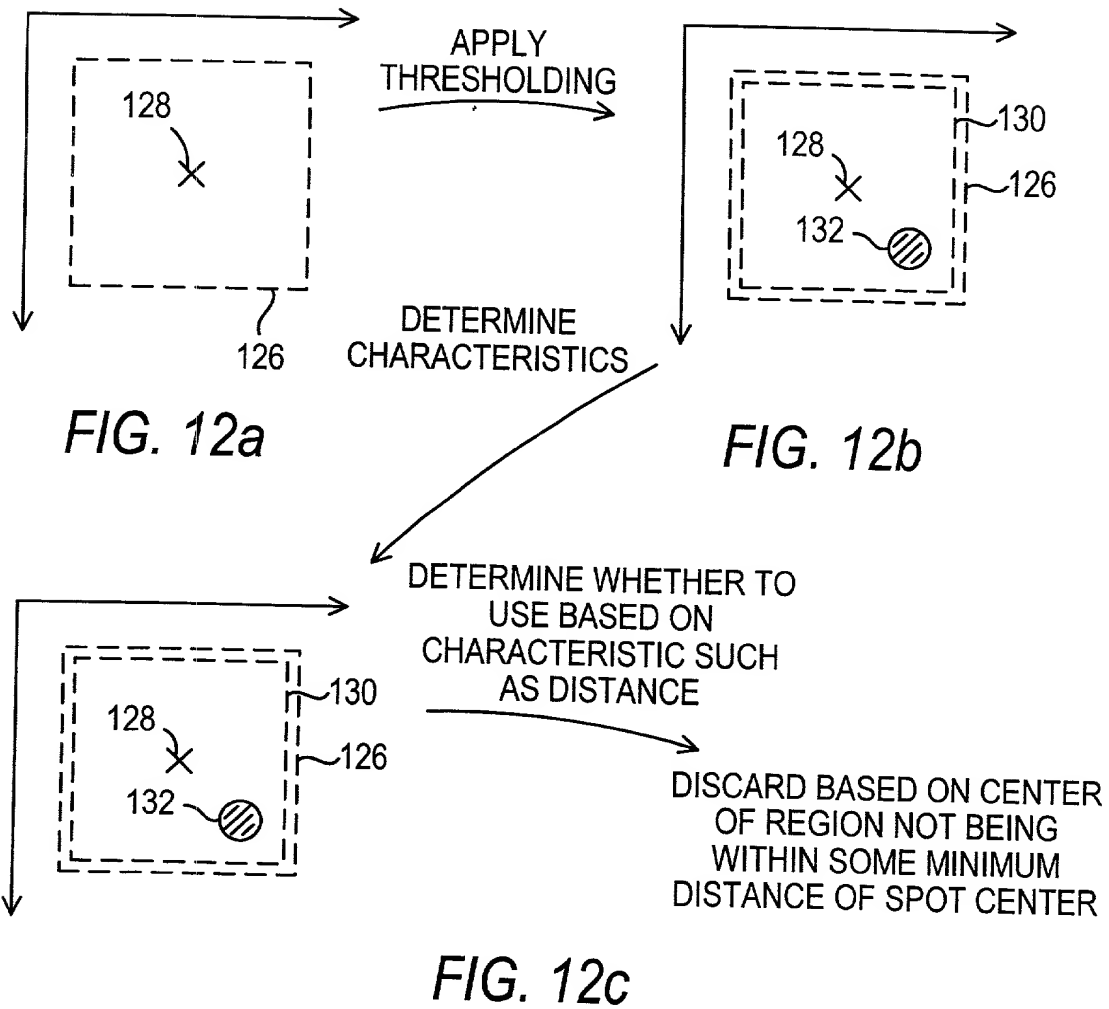


FIG. 11d

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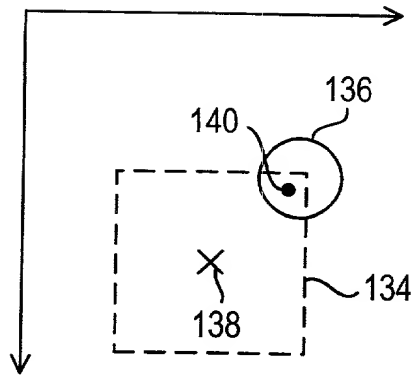


FIG. 13a

MOVE REGION TO BE CENTERED ON CALCULATED SPOT CENTER

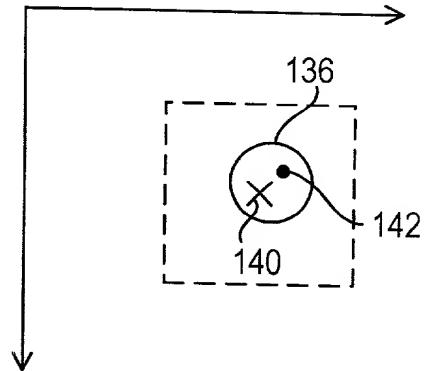


FIG. 13b

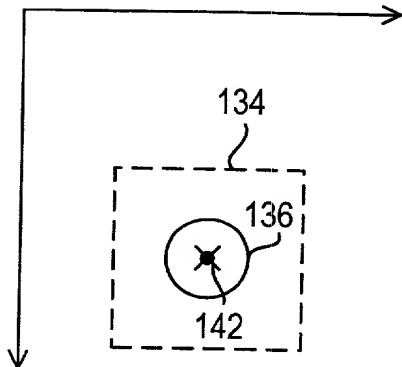


FIG. 13c

MOVE REGION TO BE CENTERED ON CALCULATED SPOT CENTER

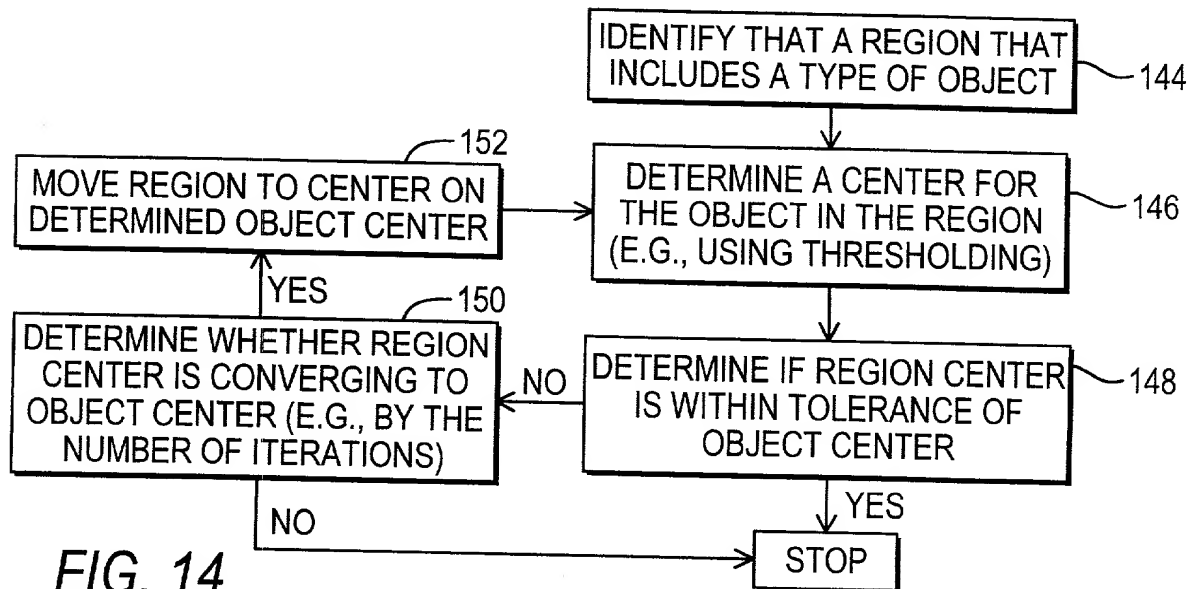


FIG. 14

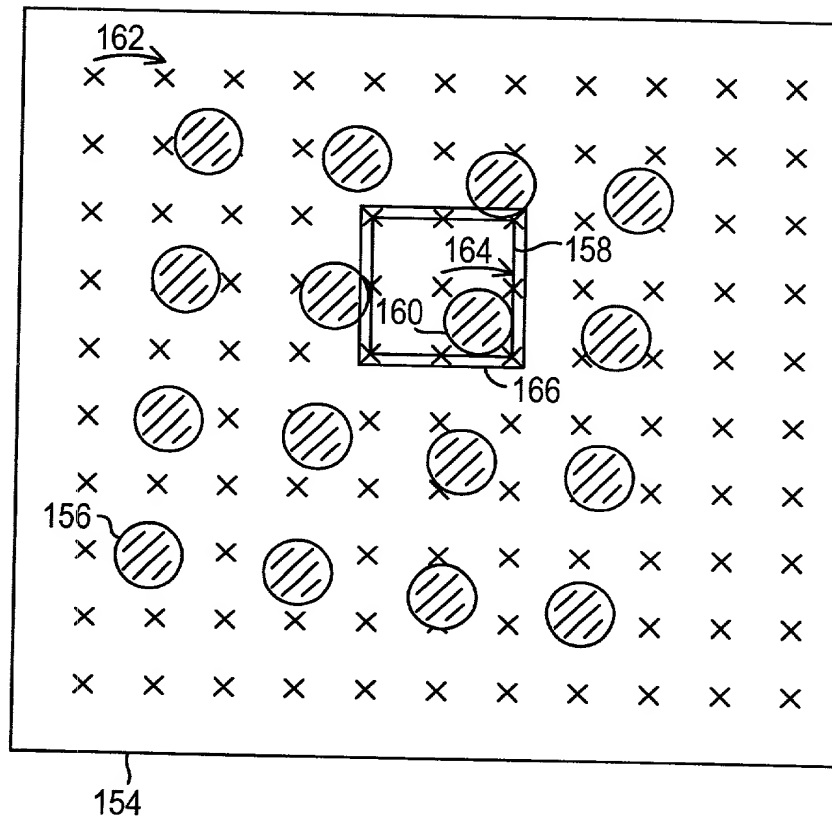


FIG. 15

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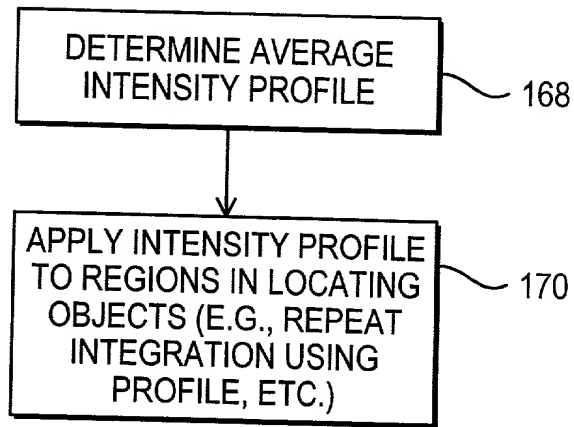


FIG. 16

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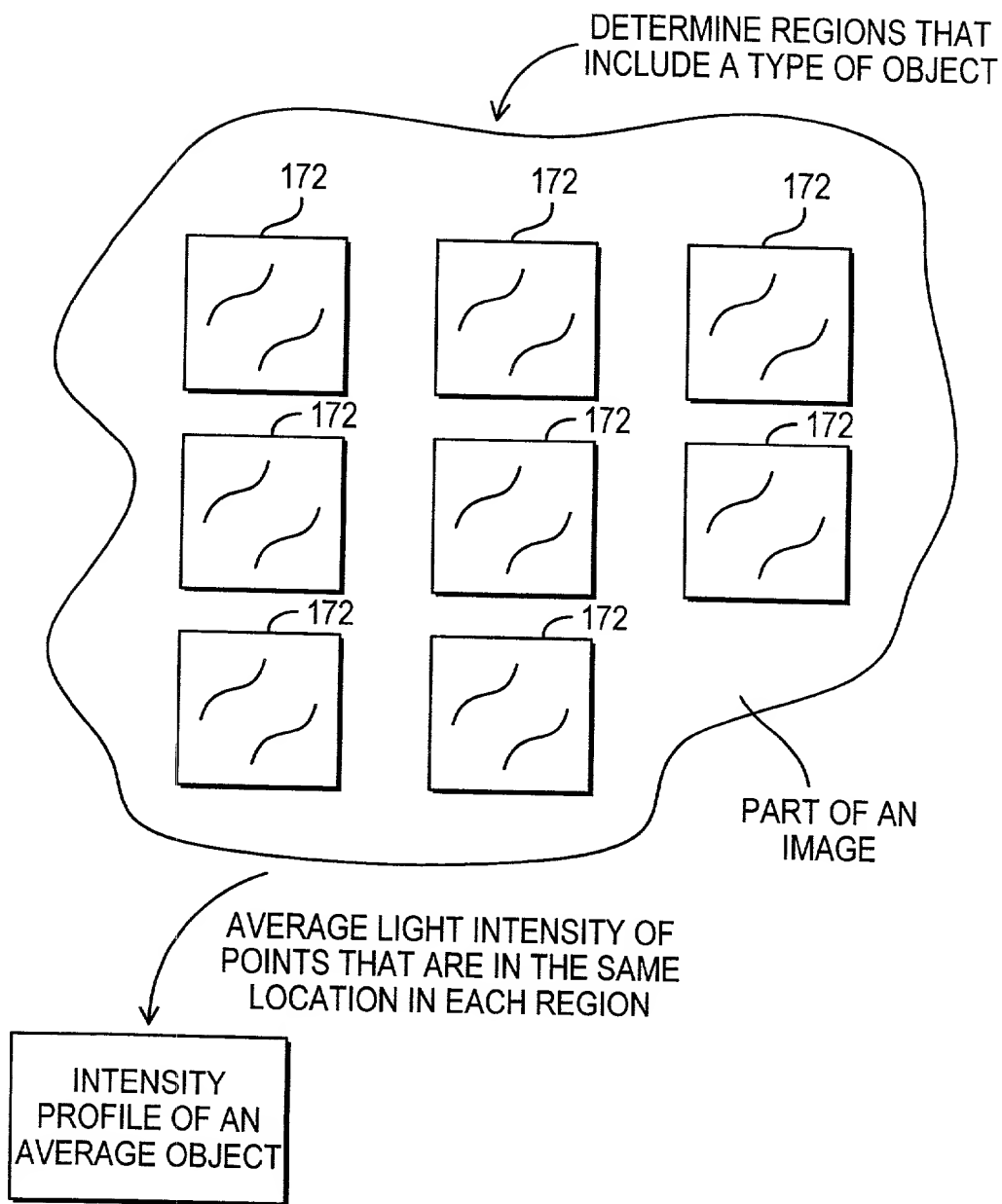


FIG. 17a

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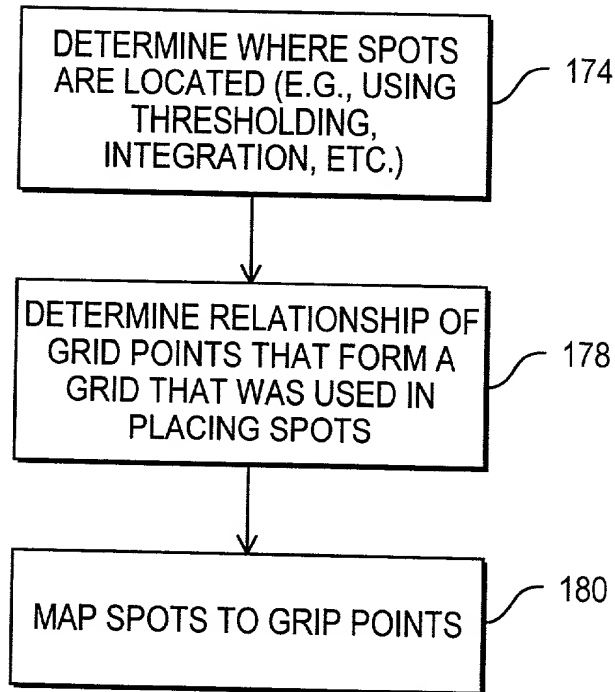
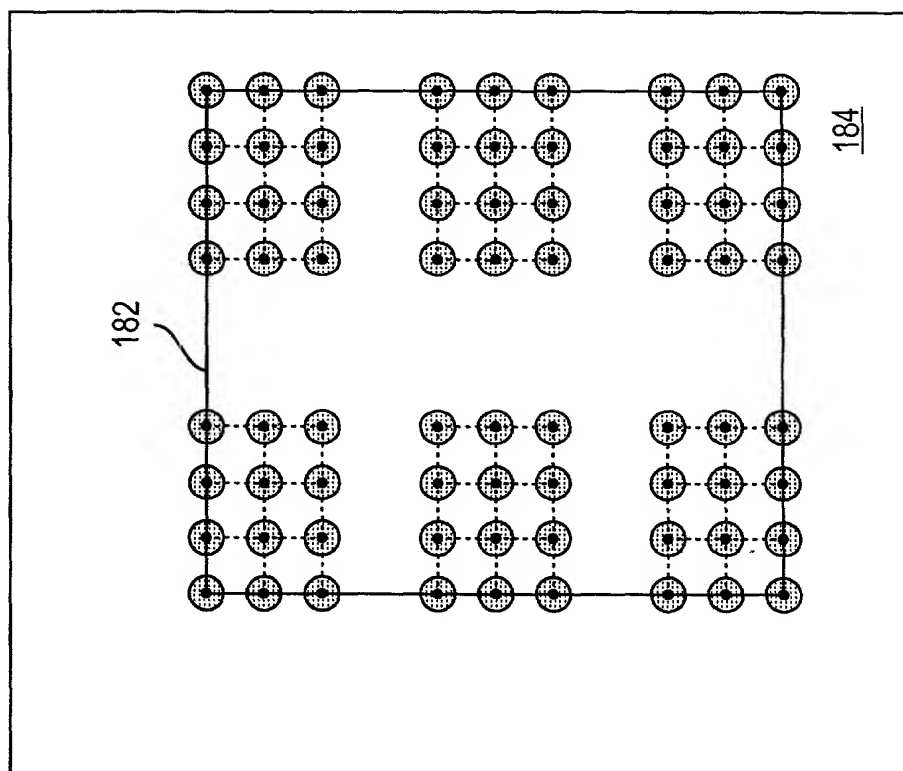
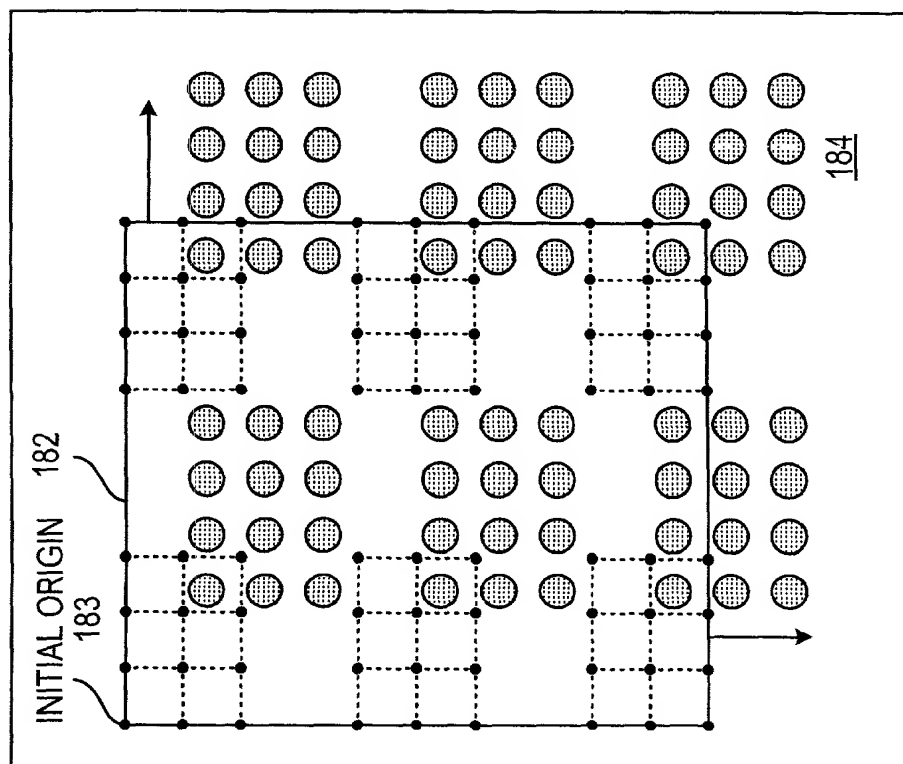


FIG. 18

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BEST ORIGIN FOR GRID FOUND



MOVING GRID ON IMAGE

FIG. 19

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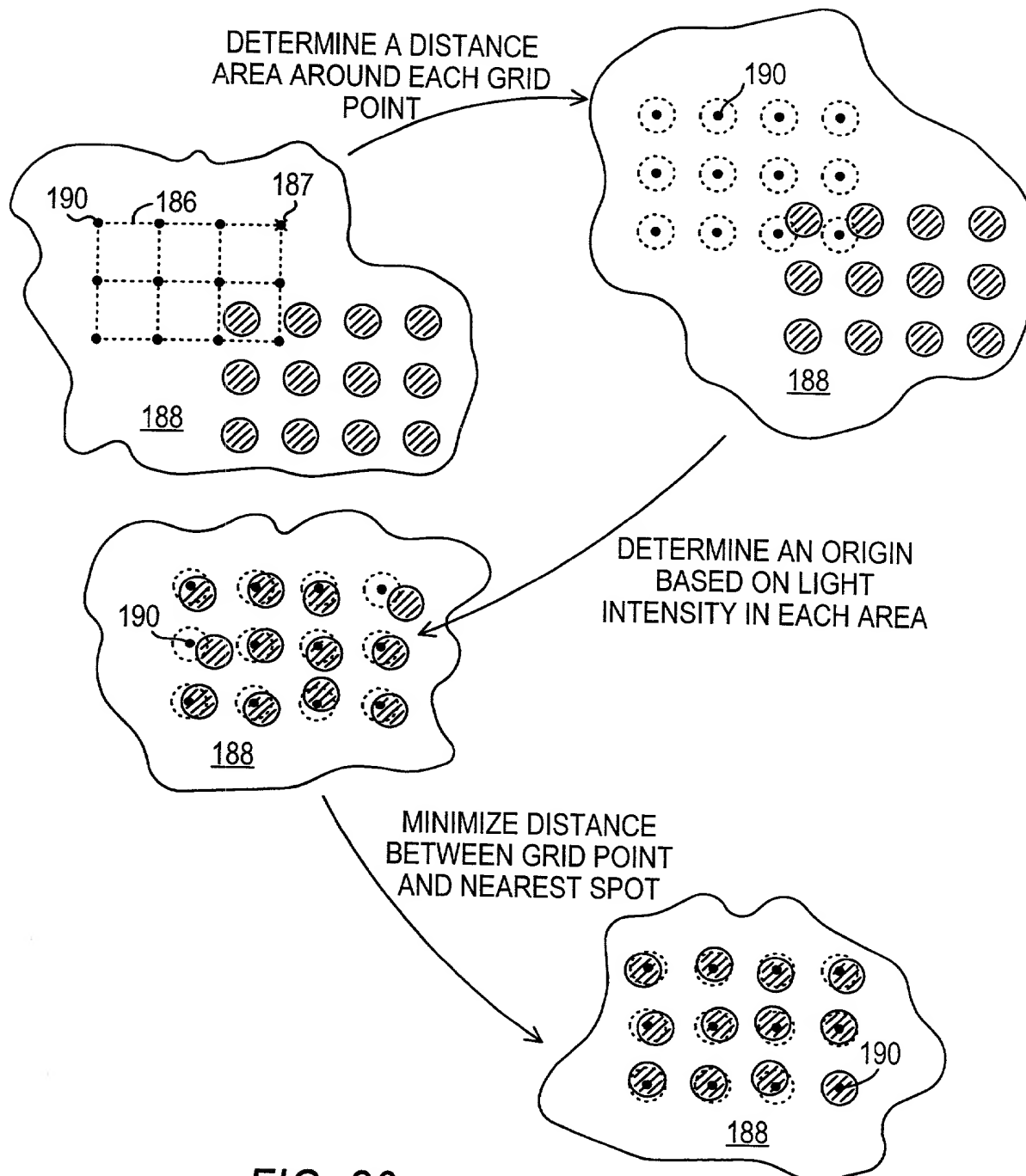
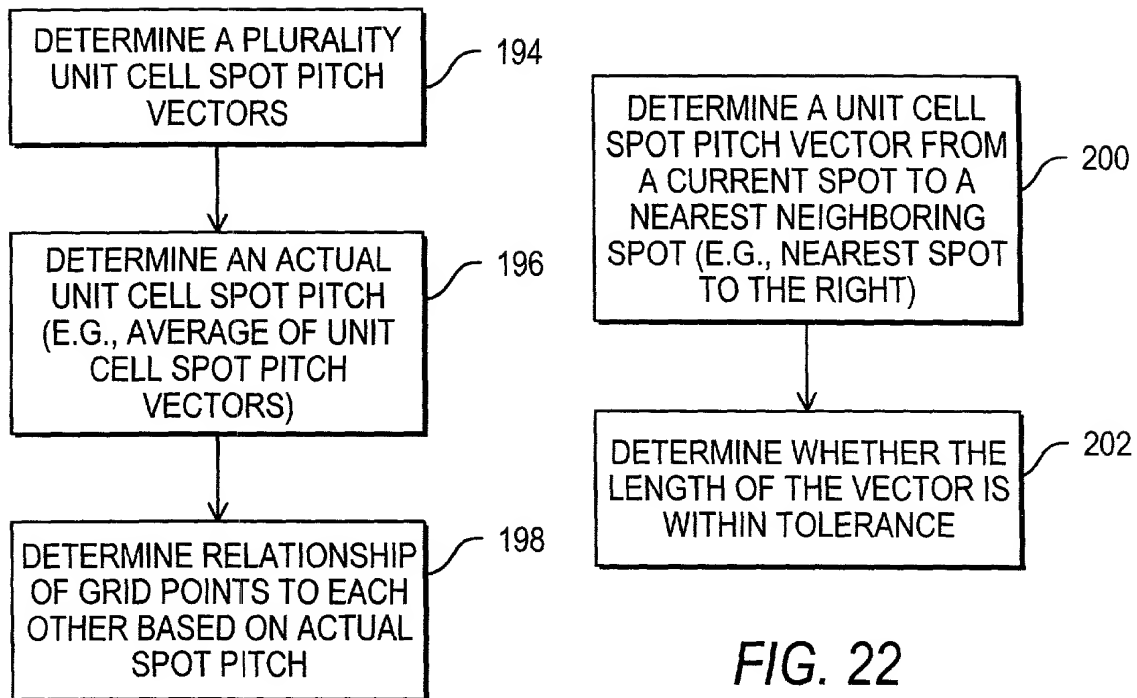


FIG. 20

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NEAREST NEIGHBOR WITHIN
TOLERANCE FOR SPOT PITCH VECTOR

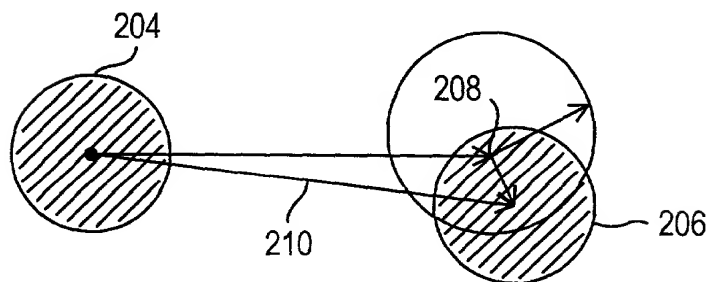


FIG. 23a

NEAREST NEIGHBOR NOT WITHIN
TOLERANCE FOR SPOT PITCH VECTOR

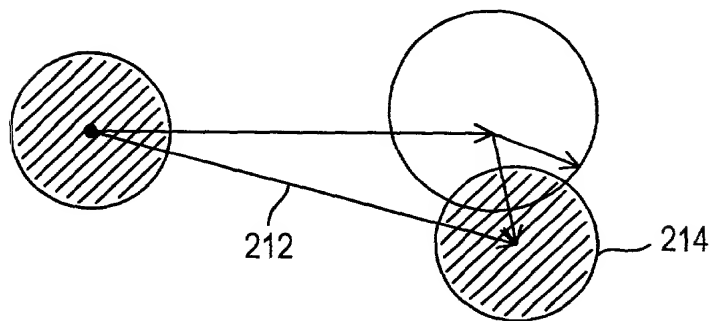


FIG. 23b

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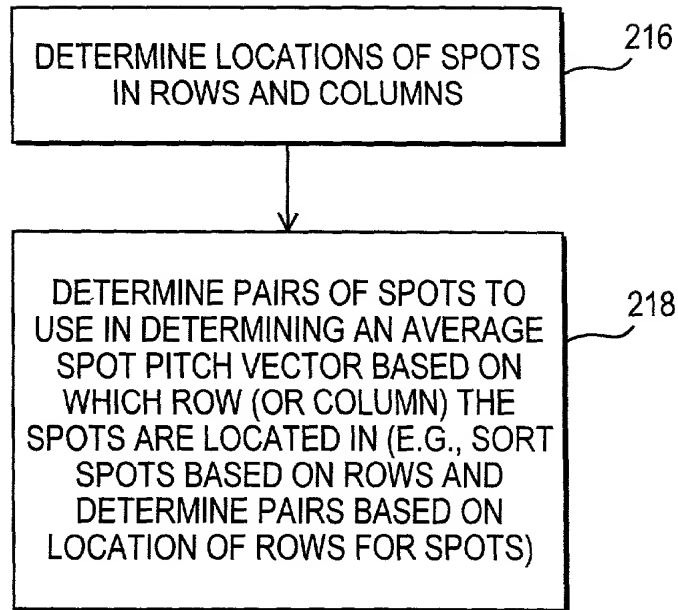


FIG. 24

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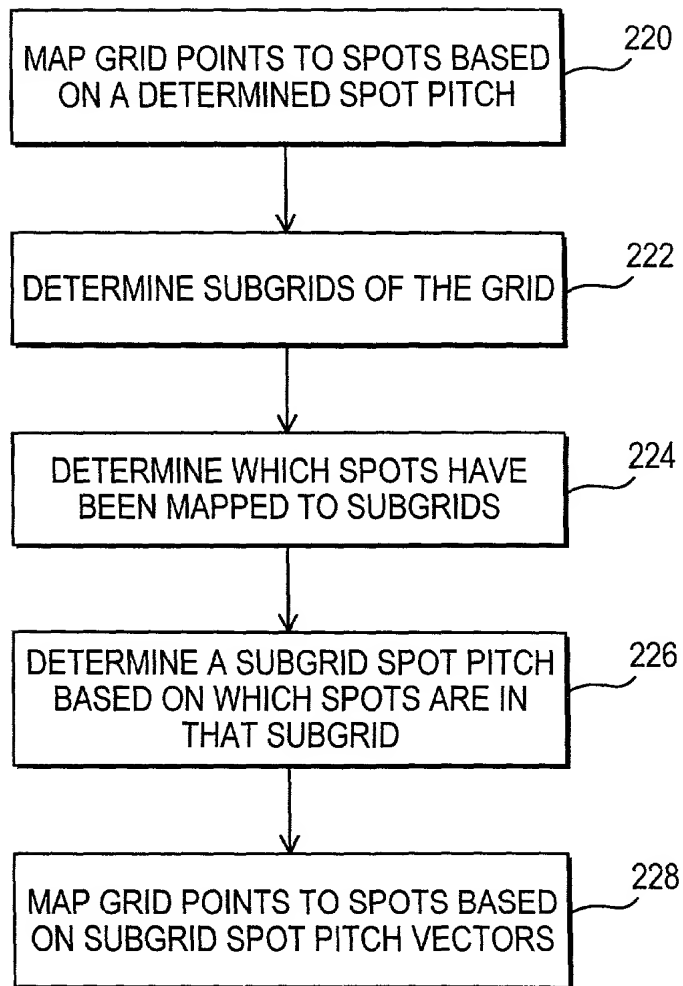


FIG. 25

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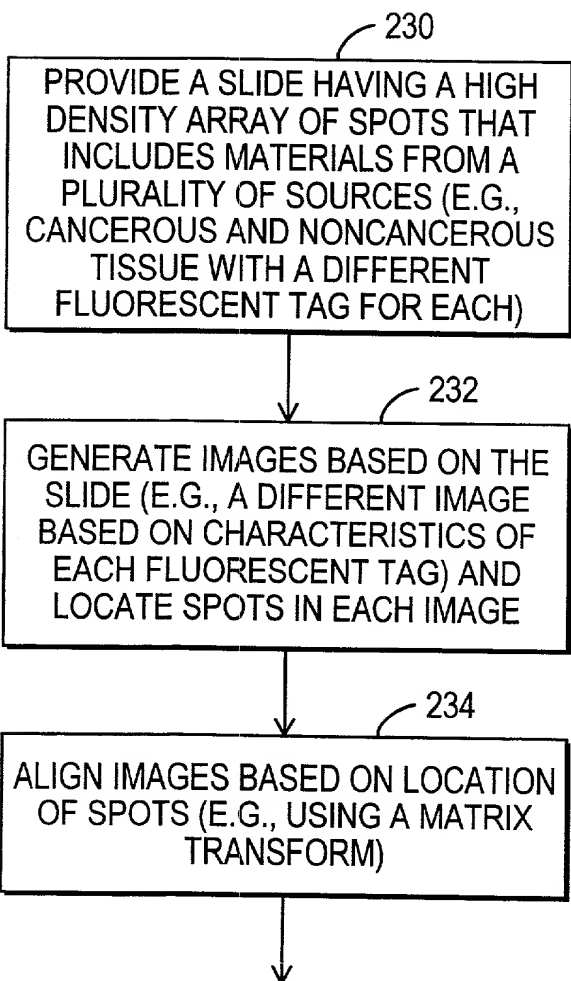


FIG. 26a

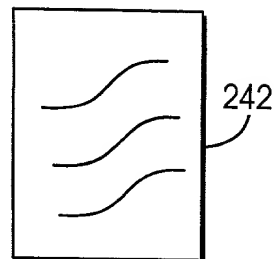


FIG. 27a

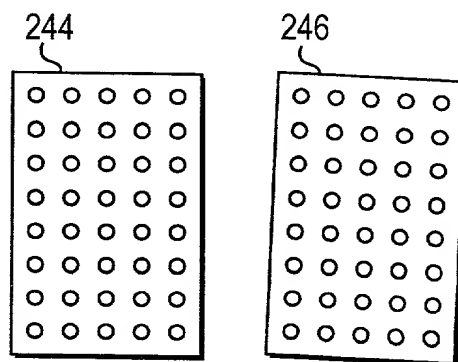


FIG. 27b

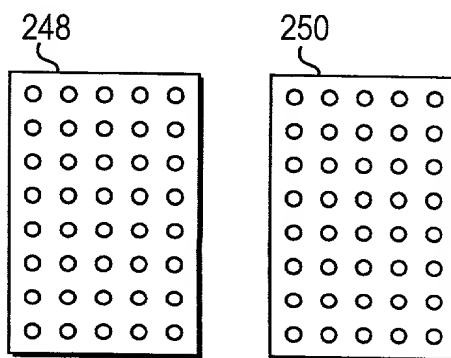


FIG. 27c

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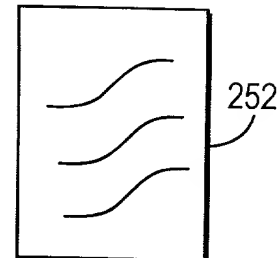
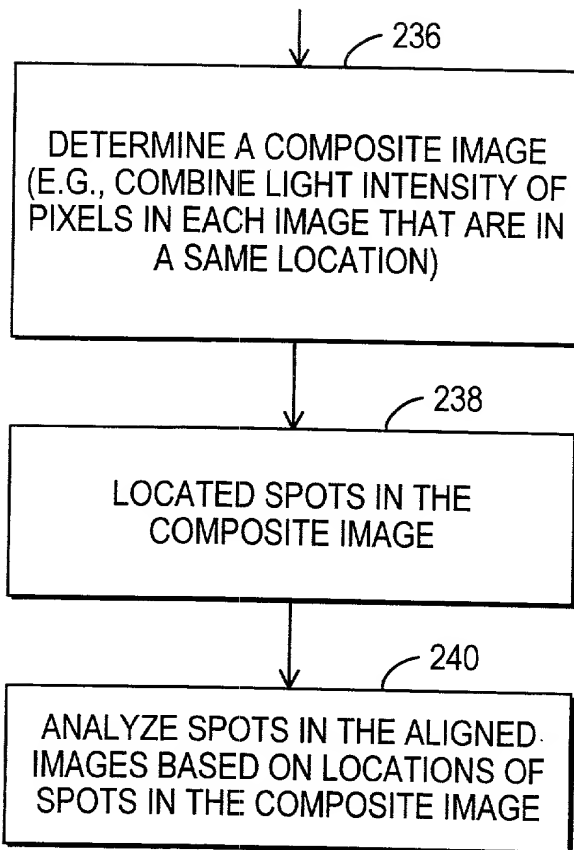


FIG. 27d

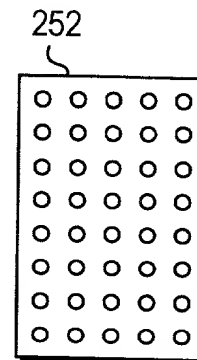


FIG. 27e

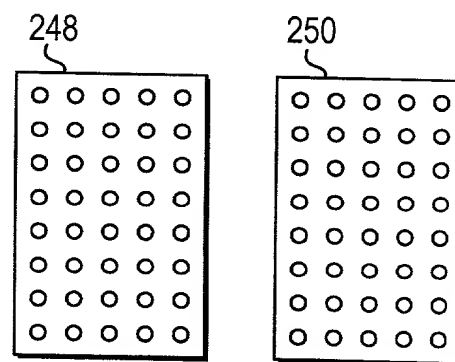


FIG. 27f

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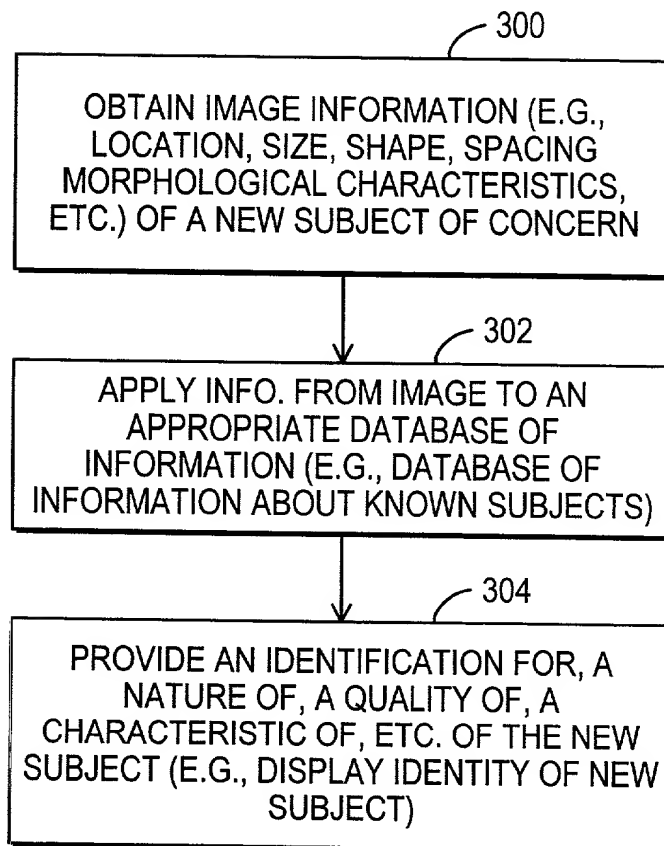


FIG. 28

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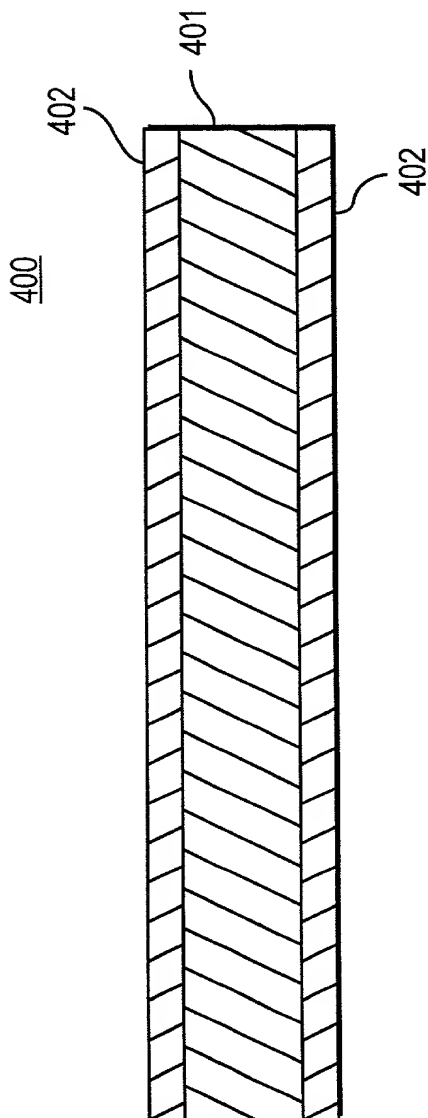


FIG. 29

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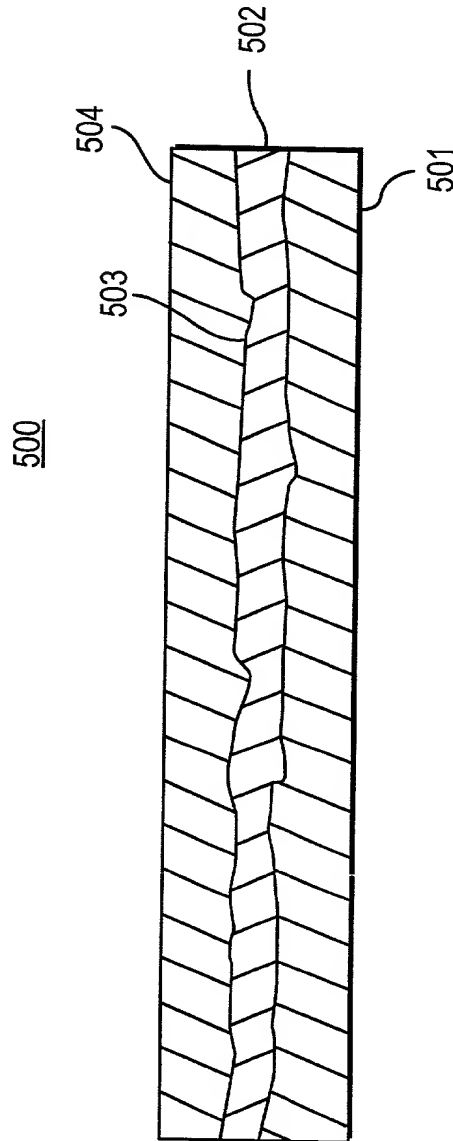


FIG. 30